Applicant: Alain CHARPENTIER Group Art Unit: Subclass Filing Date: June 22, 2006 Subclass Filing date: June 22, 2006 Subclass Filing date: June 24, 2006 Subclass Filing date: June 24, 2006 Subclass Filing date: June 20, 2006 Subclass June 20, 2006 Subc	PTO-1449					ABB Bag'd PC	IPI	1221	Progr	
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EXAMINER: /Mark Deuble/ (08/27/2008)

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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EJ/mps

Y&T June 22, 2006

^{*} English language abstract provided for the Examiner's convenience